Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | IIDA ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-3,983,021	09-1976	Henis, Jay M.	204/164
*	В	US-5,711,147	01-1998	Vogtlin et al.	60/274
*	С	US-7,070,744 B2	07-2006	Son, Geon Seog	422/186.04
*	D	US-7,011,796 B2	03-2006	Raybone et al.	422/186.04
*	Е	US-2003/0170154 A1	09-2003	Inman et al.	422/186.04
	F	US-			
	G	US-			
	Н	US-			
	-	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 0 608 619 B1	10-1997	Europe	Bayliss et al.	B01D 53/46
	0	GB 2 270 013 A	03-1994	Great Britain	Davies et al.	F01N 3/08
	Р	JP 2002-336,653 A	11-2002	Japan	Kagawa et al.	B01D 53/86
	0					
	R					
	S					
	Т			-::::::::::::::::::::::::::::::::::::::		

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	υ		
	v		
	w		
	x		

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.